

PATENT APPLICATION

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of:

GLENN CLARKE ET AL.

Application No.: 10/840,134

Filed: 05/06/2004

For: METHOD OF MAKING HIGHLY
DISCRIMINATING OPTICAL EDGE
FILTERS AND RESULTING PRODUCTS

Examiner: ASSAF, FAYEZ G.

TC/Art Unit: 2872

July 21, 2005

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

INFORMATION DISCLOSURE STATEMENT

Sir:

In compliance with the duty of disclosure under 37 C.F.R. § 1.56 and in accordance with the practice under 37 C.F.R. §§ 1.97 and 1.98, the Examiner's attention is directed to the documents listed on the enclosed PTO-1449 form. A copy of each listed document is enclosed, except for U.S. patents and published U.S. patent applications.

I hereby certify that this correspondence is being deposited with the United States Postal Service as first-class mail in an envelope addressed to: Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450 on

July 21, 2005
Date of Transmission

Daniel D. Sierchio (Reg. No. 53,591)
Printed Name

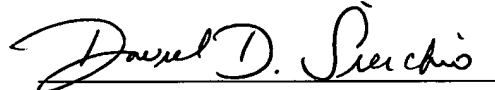
Daniel D. Sierchio
Signature

July 21, 2005
Date of Signature

Applicants' undersigned attorney may be reached by telephone at (973) 597-2500.

All correspondence should continue to be directed to our address listed below.

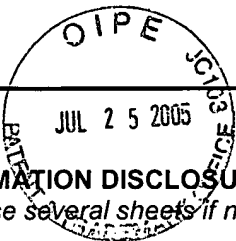
Respectfully submitted,

A handwritten signature in cursive script, reading "Daniel D. Sierchio", written over a horizontal line.

Daniel D. Sierchio
Attorney for Applicants

Registration No. 53,591

DOCKET ADMINISTRATOR
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INFORMATION DISCLOSURE CITATION (Use several sheets if necessary)	Docket Number (Optional) 15789-2	Application Number 10/840,134
	Applicant(s) GLENN CLARKE ET AL.	
	Filing Date 05/06/2004	Group Art Unit 2872

U.S. PATENT DOCUMENTS

EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
		2005/0110999	05/26/05	Erdogan et al.	356	417	
		6,809,859	10/26/04	Erdogan et al.	359	359	
		4,142,958	03/06/79	Wei et al.	204	192	
		4,793,908	12/27/88	Scott et al.	204	192.26	
		6,649,208	11/18/03	Rodgers	427	10	
		6,704,130	03/09/04	Ford et al.	359	245	
		5,656,138	08/12/97	Scobey et al.	204	192.12	
		5,512,131	04/30/96	Kumar et al.	156	655.1	

FOREIGN PATENT DOCUMENTS

EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	TRANSLATION	
							Yes	No

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

		Becker, J., "Ion-Beam Sputtering," Handbook of Optical Properties, Vol. 1, Thin Films for Optical Coatings, Ed. By R.E. Hummel and K.H. Guenther, Chapter 7, pp. 189-211, (CRC Press, Boca Raton, 1995)	
		Macleod, H. Angus, "Thin-Film Optical Filters," 3 rd Ed., Institute of Physics (2001)	
		Macleod, H.A., "Turning value monitoring of narrow-band all-dielectric thin-film optical filters," Optica Acta, Vol. 19, pp. 1-28 (1972)	
		Press, W.H., et al., The Levenberg-Marquardt method implemented under the name "mrqmin()", <u>Numerical Recipes in C: The Art of Scientific Computing</u> , 2 nd ed., Chapter 15, pp. 683-688 (1995)	
		Martin, P.J. et al., "Ion-beam-assisted deposition of thin films," Applied Optics, Vol. 22, No. 1, pp. 178-184 (1983)	
		"Interference Filters," Melles Griot, pp. 13.25-13.29	

Examiner Signature	Date Considered
EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP Section 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.	

Form PTO-A820 (also form PTO-1449)

INFORMATION DISCLOSURE CITATION
(Use several sheets if necessary)

Docket Number (Optional)
15789-2

Application Number
10/840,134

Applicant(s)
Glenn Clarke et al.

Filing Date
05/06/2004

Group Art Unit
2872

U.S. PATENT DOCUMENTS

EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
		6,518,168	02/11/03	Clem et al.	438	623	
		5,900,160	05/04/99	Whitesides et al.	216	41	
		6,623,803	09/23/03	Krivokapic	427	304	
		5,112,127	05/12/92	Carrabba et al.	356	301	
		5,712,715	01/27/98	Erdogan et al.	359	8	

FOREIGN PATENT DOCUMENTS

EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	TRANSLATION	
							Yes	No

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

		J.M.E. Harper, "Ion Beam Deposition," in <i>Thin Film Processes</i>, Ed. by J.L. Vossen and W. Kern, pp. 175-206 (Academic Press, New York, 1978).	
		U.J. Gibson, "Ion-Beam Processing of Optical Thin Films," in <i>Physics of Thin Films</i>, Vol. 13, Ed. by G. Hass and M.H. Fancombe, pp. 109-150 (Academic Press, New York, 1978).	
		J.M.E. Harper et al., "Modification of Thin Film Properties by Ion Bombardment During Deposition," in <i>Ion Bombardment Modification of Surfaces</i>, Ed. by O. Auciello and R. Kelly, from <i>Beam Modification of Materials</i>, Vol. 1, pp. 127-162 (Elsevier, Amsterdam, 1984).	
		W.H. Teukolsky et al., <i>Numerical Recipes</i>, "Numerical Recipes in C: The Art of Scientific Computing," 2nd ed., Cambridge University Press, Cambridge, Chapter 15.7, pp. 699-706 (1995).	

Examiner Signature

Date Considered

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